# Special Issue

# Image Analysis for Product Quality Control

### Message from the Guest Editors

Image analysis carried out in industry using various types of vision systems is performed for the purpose of quick, noncontact, and multiparameter quality assessment of the product. It is introduced in many industries, enabling the implementation of a very wide range of control and measurement tasks. It has become a part of quality control systems operating in factories and is at the same time a source of product data collected by company databases supporting MESs (manufacturing execution systems). At the same time, image analysis is used as part of controlling the parameters of the production process, e.g., in tasks of positioning machines and robots, controlling tool wear or checking the wear of machine parts. Expanding the scope of image analysis application is associated with the development of new 2D and 3D imaging methods, increasing the resolution of matrices and optical systems, and the introduction of new algorithms as part of using artificial intelligence.

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### Deadline for manuscript submissions

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As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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